



3.3V CMOS 18-BIT READ/WRITE BUFFER WITH BUS-HOLD

IDT74ALVCH16701

FEATURES:

- 0.5 MICRON CMOS Technology
- Typical $t_{sk(0)}$ (Output Skew) < 250ps
- ESD > 2000V per MIL-STD-883, Method 3015;
> 200V using machine model (C = 200pF, R = 0)
- 0.635mm pitch SSOP, 0.50mm pitch TSSOP,
and 0.40mm pitch TVSOP packages
- Extended commercial range of - 40°C to + 85°C
- $V_{cc} = 3.3V \pm 0.3V$, Normal Range
- $V_{cc} = 2.7V$ to 3.6V, Extended Range
- $V_{cc} = 2.5V \pm 0.2V$
- CMOS power levels (0.4μW typ. static)
- Rail-to-Rail output swing for increased noise margin

Drive Features for ALVCH16701:

- High Output Drivers: ±24mA
- Suitable for heavy loads

APPLICATIONS:

- 3.3V High Speed Systems
- 3.3V and lower voltage computing systems

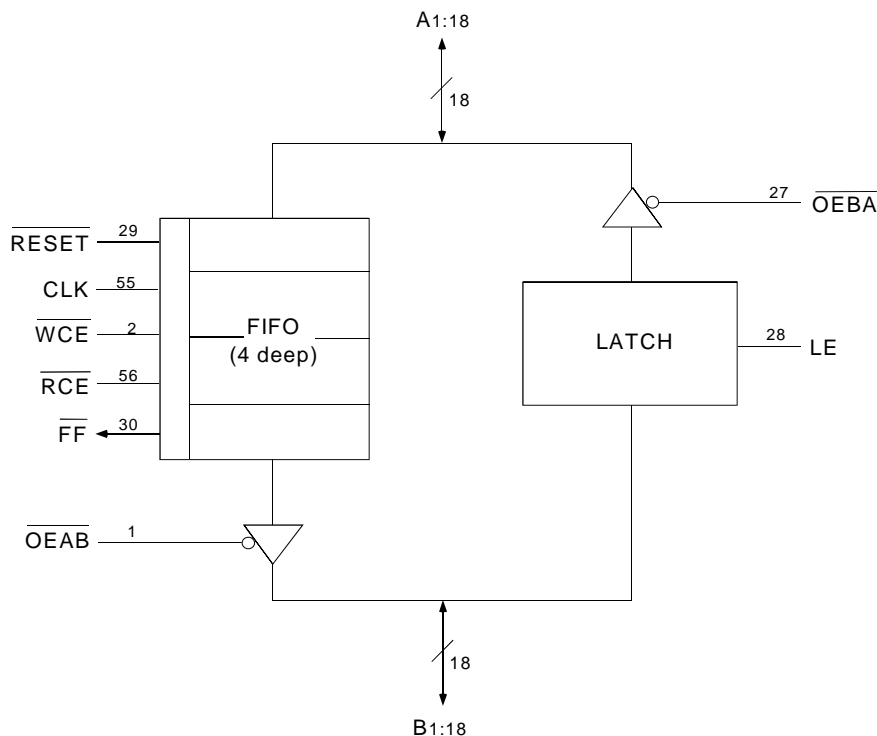
DESCRIPTION:

This 18-bit read/write buffer is built using advanced dual metal CMOS technology. The ALVCH16701 is equipped with a four deep FIFO and a read-back latch. It can be used as a read/write buffer between a CPU and a memory or to interface a high-speed bus and a slow peripheral. The A-to-B (write) path has a four deep FIFO for pipelined operations. The FIFO can be reset and a FIFO full condition is indicated by the full flag (FF). The B-to-A (read) path has a latch.

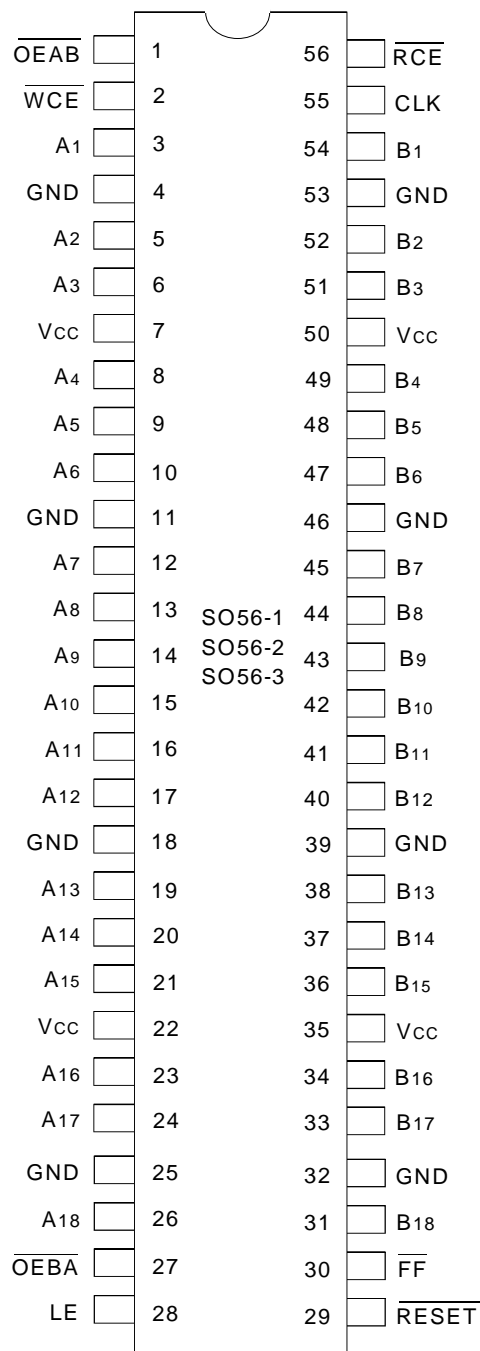
The ALVCH16701 has been designed with a ±24mA output driver. This driver is capable of driving a moderate to heavy load while maintaining speed performance.

The ALVCH16701 has "bus-hold" which retains the inputs' last state whenever the input goes to a high impedance. This prevents floating inputs and eliminates the need for pull-up/down resistor.

FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATION



SSOP/
TSSOP/TVSOP
TOP VIEW

ABSOLUTE MAXIMUM RATING (1)

Symbol	Description	Max.	Unit
VTERM ⁽²⁾	Terminal Voltage with Respect to GND	- 0.5 to + 4.6	V
VTERM ⁽³⁾	Terminal Voltage with Respect to GND	- 0.5 to V _{CC} + 0.5	V
TSTG	Storage Temperature	- 65 to + 150	°C
IOUT	DC Output Current	- 50 to + 50	mA
I _{IK}	Continuous Clamp Current, V _I < 0 or V _I > V _{CC}	± 50	mA
I _{OK}	Continuous Clamp Current, V _O < 0	- 50	mA
I _{CC}	Continuous Current through each V _{CC} or GND	± 100	mA

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NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- V_{CC} terminals.
- All terminals except V_{CC}.

CAPACITANCE (T_A = +25°C, f = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	5	7	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0V	7	9	pF
C _{I/O}	I/O Port Capacitance	V _{IN} = 0V	7	9	pF

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NOTE:

- As applicable to the device type.

PIN DESCRIPTION

Pin Names	I/O	Description
A1-18	I/O	18 bit I/O port ⁽¹⁾
B1-18	I/O	18 bit I/O port ⁽¹⁾
CLK	I	Clock for write path FIFO. Clocks data into FIFO when \overline{WCE} is low, clocks data out of FIFO when \overline{RCE} is low. When FIFO is full all further writes to the FIFO are inhibited. When FIFO is empty all reads from the FIFO are inhibited. CLK also resets the FIFO when \overline{RESET} is low.
\overline{WCE}	I	Enable pin for FIFO input clock.
\overline{RCE}	I	Enable pin for FIFO output clock.
\overline{FF}	O	Write path FIFO full flag. Goes low when FIFO is full.
\overline{RESET}	I	Synchronous FIFO reset - when low CLK resets the FIFO. The FIFO pointers are initialized to the "empty" condition and FIFO output is forced high (all ones). The FIFO full flag (\overline{FF}) will be high immediately after reset.
\overline{OEAB}	I	Output enable pin for B port
\overline{OEBA}	I	Output enable pin for A port
LE	I	Read path latch enable pin. When high, data flows transparently from B port to A port, B data is latched on the falling edge of LE.

NOTE:

1. These pins have "Bus-Hold." All other pins are standard inputs, outputs, or I/Os.

FUNCTION DESCRIPTION

This device is useful as a read/write buffer for modular high end designs. It provides multi-level buffering in the write path and single deep buffering in the read path, and is suited to write back cache implementation. The read path provides a transparent latch.

The four deep FIFO uses one clock with two clock enable pins, \overline{WCE} and \overline{RCE} to clock data in and out. The FIFO has an external full flag which goes LOW when the FIFO is full. Internal read and write pointers keep track of the words stored in the FIFO. A write attempt to a full FIFO is ignored. An attempt read from an empty FIFO will have no effect and the last read data remains at the output of the FIFO.

The FIFO may be reset by the synchronous \overline{RESET} input. This resets the read and write pointers to the original "empty" condition and also sets all B outputs = 1. Simultaneous read and write attempts (clock data into FIFO as well as clock data out of FIFO) are possible except on FIFO empty and full boundaries. When the FIFO is empty, and a simultaneous read and write is attempted, the read is ignored while the write is executed. If the same is attempted when the FIFO is full, the write is ignored while the read is executed. Normal operation of the four deep FIFO in the write path is independent of the read path operation.

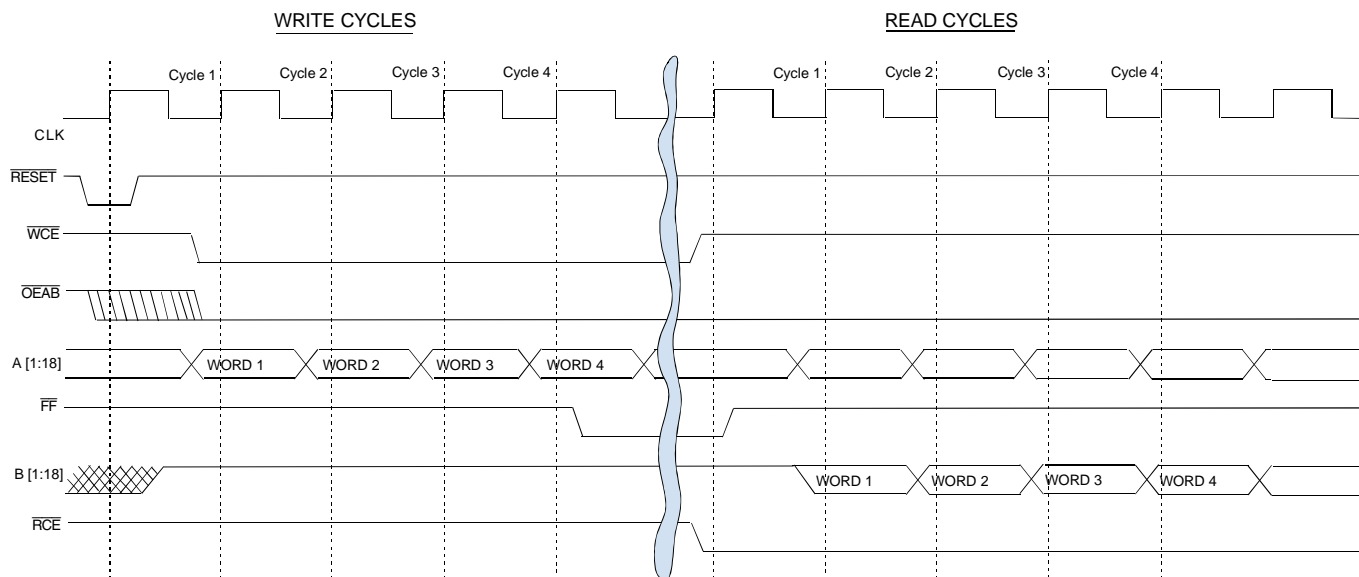
FUNCTION TABLE⁽¹⁾

INPUTS					OUTPUTS		NOTES
\overline{OEBA}	\overline{OEAB}	LE	\overline{RESET}	CLK	Ax	Bx	
H	H	H	H	↑	Q(B) Bus Hold	Q ₀ (A) -4CLKS Bus Hold	
L	H	H	H	↑	B to A		Transparent Mode
L	H	L	H	↑	Q ₀ (B)		
H	H	X	H	↑	Q ₀ (A) Bus Hold	Q ₀ (B) Bus Hold	
H	L	X	H	↑		A to B - 4 CLKs	
L	L	L	H	↑	Q ₀ (B) Bus Hold	Q ₀ (B) - 4 CLKs Bus Hold	Case not recommended

NOTE:

1. H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
↑ = LOW-to-HIGH Transition

TIMING DIAGRAM



DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Condition: $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$

Symbol	Parameter	Test Conditions		Min.	Typ. ⁽¹⁾	Max.	Unit
V _{IH}	Input HIGH Voltage Level	V _{CC} = 2.3V to 2.7V		1.7	—	—	V
		V _{CC} = 2.7V to 3.6V		2	—	—	
V _{IL}	Input LOW Voltage Level	V _{CC} = 2.3V to 2.7V		—	—	0.7	V
		V _{CC} = 2.7V to 3.6V		—	—	0.8	
I _{IH}	Input HIGH Current	V _{CC} = 3.6V	V _I = V _{CC}	—	—	± 5	μA
I _{IL}	Input LOW Current	V _{CC} = 3.6V	V _I = GND	—	—	± 5	
I _{OZH} I _{OZL}	High Impedance Output Current (3-State Output pins)	V _{CC} = 3.6V		—	—	± 10	μA
				V _O = V _{CC}	—	—	
V _{IK}	Clamp Diode Voltage	V _{CC} = 2.3V, I _{IN} = -18mA		—	-0.7	-1.2	V
V _H	Input Hysteresis	V _{CC} = 3.3V		—	100	—	mV
I _{CC1} I _{CC2} I _{CC3}	Quiescent Power Supply Current	V _{CC} = 3.6V V _{IN} = GND or V _{CC}		—	0.1	40	μA
ΔI _{CC}	Quiescent Power Supply Current Variation	One input at V _{CC} - 0.6V, other inputs at V _{CC} or GND		—	—	750	

NOTE:

1. Typical values are at V_{CC} = 3.3V, +25°C ambient.

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BUS-HOLD CHARACTERISTICS

Symbol	Parameter ⁽¹⁾	Test Conditions		Min.	Typ. ⁽²⁾	Max.	Unit
IBHH	Bus-Hold Input Sustain Current	V _{CC} = 3.0V	V _I = 2.0V	- 75	—	—	μA
IBHL			V _I = 0.8V	75	—	—	
IBHH	Bus-Hold Input Sustain Current	V _{CC} = 2.3V	V _I = 1.7V	- 45	—	—	μA
IBHL			V _I = 0.7V	45	—	—	
IBHHO	Bus-Hold Input Overdrive Current	V _{CC} = 3.6V	V _I = 0 to 3.6V	—	—	± 500	μA
IBHLO							

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NOTES:

1. Pins with Bus-hold are identified in the pin description.
2. Typical values are at V_{CC} = 3.3V, +25°C ambient.

OPERATING CHARACTERISTICS, T_A = 25°C

Symbol	Parameter	Test Conditions	V _{CC} = 2.5V ± 0.2V		V _{CC} = 3.3V ± 0.3V		Unit
			Typical	Typical	Typical	Typical	
CPD	Power Dissipation Capacitance Outputs enabled	C _L = 0pF, f = 10Mhz	CLK Toggling	28	31	pF	
			One Bit Toggling	26	29		
CPD	Power Dissipation Capacitance Outputs enabled		CLK Toggling	10	11	pF	
			One Bit Toggling	9	10		

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Max.	Unit
VOH	Output HIGH Voltage	V _{CC} = 2.3V to 3.6V	I _{OH} = - 0.1mA	V _{CC} - 0.2	—	V
		V _{CC} = 2.3V	I _{OH} = - 6mA	2	—	
		V _{CC} = 2.3V	I _{OH} = - 12mA	1.7	—	
		V _{CC} = 2.7V		2.2	—	
		V _{CC} = 3.0V		2.4	—	
		V _{CC} = 3.0V	I _{OH} = - 24mA	2	—	
VOL	Output LOW Voltage	V _{CC} = 2.3V to 3.6V	I _{OL} = 0.1mA	—	0.2	V
		V _{CC} = 2.3V	I _{OL} = 6mA	—	0.4	
			I _{OL} = 12mA	—	0.7	
		V _{CC} = 2.7V	I _{OL} = 12mA	—	0.4	
		V _{CC} = 3.0V	I _{OL} = 24mA	—	0.55	

NOTE:

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1. V_{IH} and V_{IL} must be within the min. or max. range shown in the DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE table for the appropriate V_{CC} range. T_A = - 40°C to + 85°C.

SWITCHING CHARACTERISTICS (1)

Parameter	Test Conditions	V _{CC} = 2.7V		V _{CC} = 3.3V ± 0.3V		Unit	
		Min.	Max.	Min.	Max.		
PROPAGATION DELAYS							
1	B ₁₋₁₈ to A ₁₋₁₈	Read path/latch	—	—	1.5	4.5	ns
2	LE (LOW to HIGH) to A ₁₋₁₈	Read path/latch	—	—	1.5	4.5	ns
3	CLK to \overline{F}	Write path	—	—	1.5	5.5	ns
4	CLK to B ₁₋₁₈	Write path	—	—	1.5	5.5	ns
5	Output Skew ⁽²⁾	Write path	—	—	—	1	ns
SETUP & HOLD TIMES							
6	A ₁₋₁₈ to CLK (LOW to HIGH) Setup	Write path	—	—	1.8	—	ns
7	A ₁₋₁₈ to CLK (LOW to HIGH) Hold	Write path	—	—	1	—	ns
8	B ₁₋₁₈ to LE (HIGH to LOW) Setup	Read path/latch	—	—	1.8	—	ns
9	B ₁₋₁₈ to LE (HIGH to LOW) Hold	Read path/latch	—	—	1	—	ns
10	\overline{WCE} , \overline{RCE} (LOW) to CLK Setup	Write path	—	—	3.5	—	ns
11	\overline{WCE} , \overline{RCE} (LOW) to CLK Hold	Write path	—	—	0.5	—	ns
12	\overline{RESET} (LOW) to CLK Setup	Write path	—	—	1.8	—	ns
13	\overline{RESET} (LOW) to CLK Hold	Write path	—	—	1	—	ns
ENABLE & DISABLE TIMES							
14	\overline{OEBA} LOW to A ₁₋₁₈ Enable	Write path	—	—	1.5	6	ns
15	\overline{OEBA} HIGH to A ₁₋₁₈ Disable	Write path	—	—	1.5	5.7	ns
16	\overline{OEAB} LOW to B ₁₋₁₈ Enable	Read path	—	—	1.5	6	ns
17	\overline{OEAB} HIGH to B ₁₋₁₈ Disable	Read path	—	—	1.5	5.7	ns
MINIMUM PULSE WIDTHS							
18	CLK HIGH or LOW Pulse Width	Write path	—	—	5	—	ns
19	LE HIGH Pulse Width	Read path/latch	—	—	5	—	ns
19	Clock Frequency		—	—		83	MHz
20	Clock Cycle Time		—	—	12	—	ns

NOTES:

1. See test circuits and waveforms. T_A = – 40°C to + 85°C.
2. Skew between any two outputs of the same package and switching in the same direction.

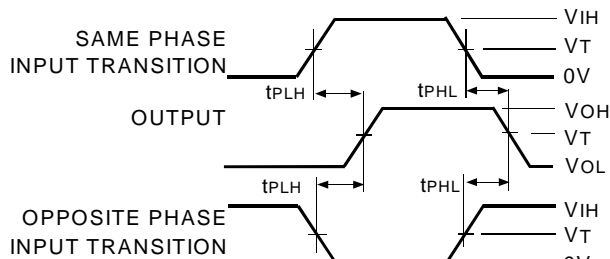
TEST CIRCUITS AND WAVEFORMS

TEST CONDITIONS

Symbol	V _{CC} (1)= 3.3V±0.3V	V _{CC} (1)= 2.7V	V _{CC} (2)= 2.5V±0.2V	Unit
V _{LOAD}	6	6	2 x V _{CC}	V
V _{IH}	2.7	2.7	V _{CC}	V
V _T	1.5	1.5	V _{CC} / 2	V
V _{LZ}	300	300	150	mV
V _{HZ}	300	300	150	mV
C _L	50	50	30	pF

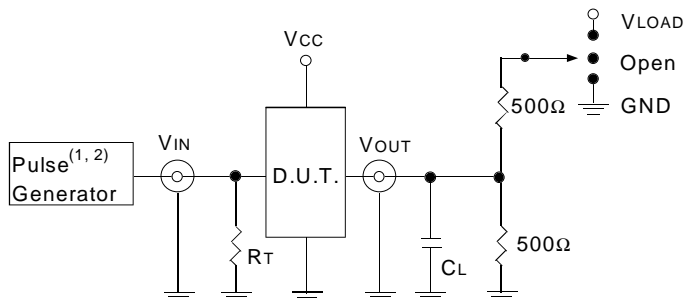
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PROPAGATION DELAY



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TEST CIRCUITS FOR ALL OUTPUTS



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DEFINITIONS:

C_L = Load capacitance: includes jig and probe capacitance.

R_T = Termination resistance: should be equal to Z_{OUT} of the Pulse Generator.

NOTES:

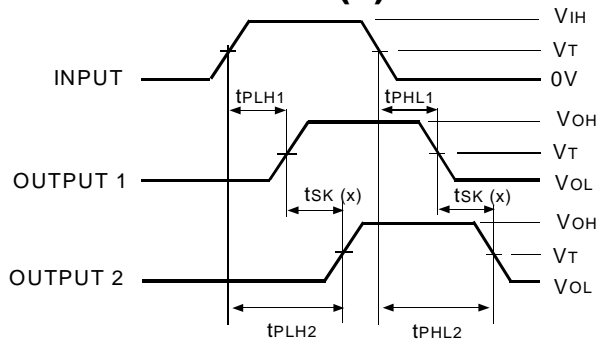
1. Pulse Generator for All Pulses: Rate ≤ 10MHz; t_F ≤ 2.5ns; t_R ≤ 2.5ns.
2. Pulse Generator for All Pulses: Rate ≤ 10MHz; t_F ≤ 2ns; t_R ≤ 2ns.

SWITCH POSITION

Test	Switch
Open Drain Disable Low Enable Low	V _{LOAD}
Disable High Enable High	GND
All Other tests	Open

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OUTPUT SKEW - TSK (x)



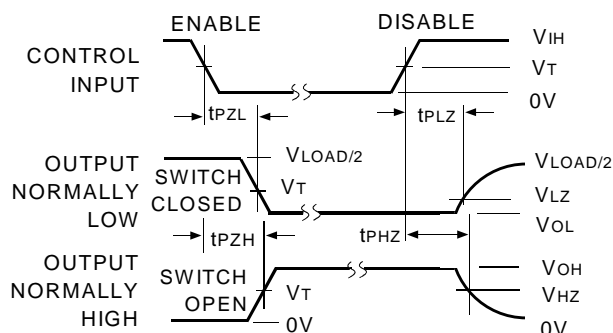
$$t_{SK}(x) = |t_{PLH2} - t_{PLH1}| \text{ or } |t_{PHL2} - t_{PHL1}|$$

ALVC Link

NOTES:

1. For t_{SK}(o) OUTPUT1 and OUTPUT2 are any two outputs.
2. For t_{SK}(b) OUTPUT1 and OUTPUT2 are in the same bank.

ENABLE AND DISABLE TIMES

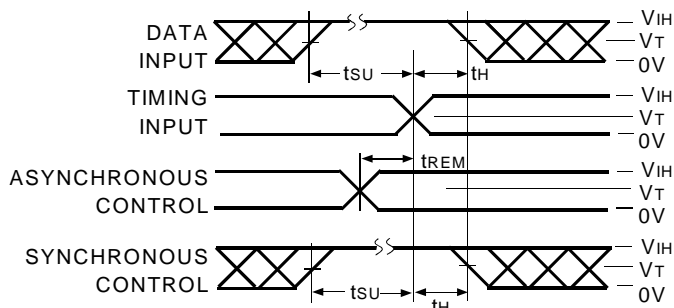


ALVC Link

NOTE:

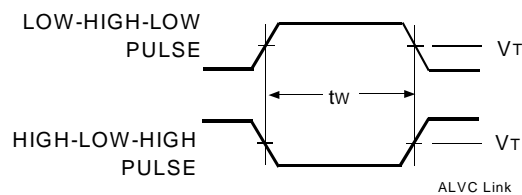
1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.

SET-UP, HOLD, AND RELEASE TIMES



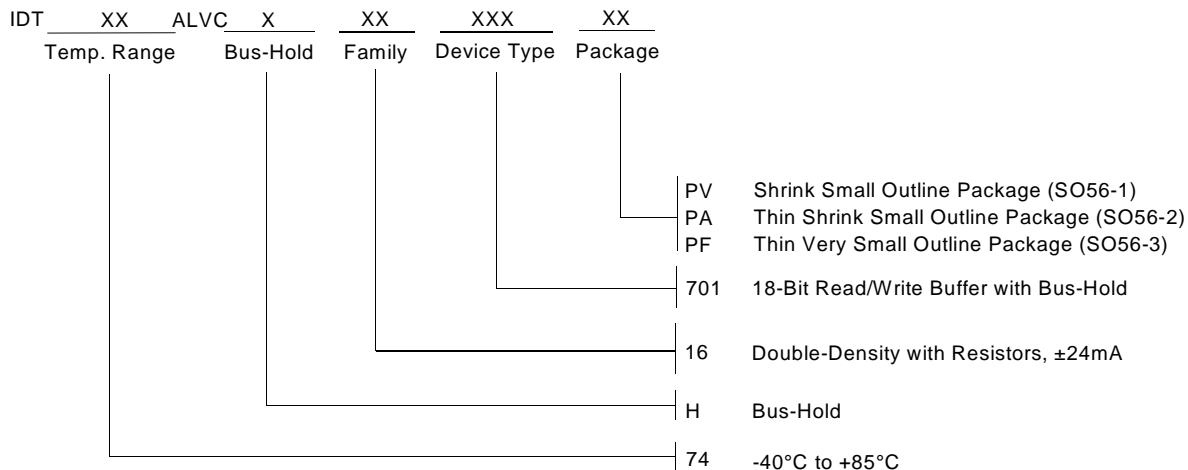
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PULSE WIDTH



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ORDERING INFORMATION



CORPORATE HEADQUARTERS
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 Santa Clara, CA 95054

for SALES:
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